

GA50JT06-258

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600 V

1.3 V

50 A

25 mΩ

 V_{DS}

 I_D

V_{DS(ON)}

R_{DS(ON)}

Normally – OFF Silicon Carbide Junction Transistor

Features

- 250 °C maximum operating temperature
- Temperature independent switching performance
- Gate oxide free SiC switch
- Suitable for connecting an anti-parallel diode
- Positive temperature coefficient for easy paralleling
- Low gate charge
- · Low intrinsic capacitance

Advantages

- SiC transistor most compatible with existing Si gate-drivers
- Low switching losses
- Higher efficiency
- High temperature operation
- · High short circuit withstand capability

Package RoHS Compliant





TO-258

Applications

- Down Hole Oil Drilling, Geothermal Instrumentation
- Hybrid Electric Vehicles (HEV)
- Solar Inverters
- Switched-Mode Power Supply (SMPS)
- Power Factor Correction (PFC)
- Induction Heating
- Uninterruptible Power Supply (UPS)
- Motor Drives

Absolute Maximum Ratings

Parameter	Symbol	Conditions	Values	Unit
Drain – Source Voltage	V _{DS}	$V_{GS} = 0 V$	600	V
Continuous Drain Current	Ι _D	120 °C < T _C < 200 °C	50	А
Gate Peak Current	I _{GM}		10	А
Turn-Off Safe Operating Area	RBSOA	T_{VJ} = 250 °C, I_G = 1 A, Clamped Inductive Load	I _{D,max} = 50 @ V _{DS} ≤ V _{DSmax}	А
Short Circuit Safe Operating Area	SCSOA	T_{VJ} = 250 °C, I _G = 2.5 A, V _{DS} = 400 V, Non Repetitive	20	μs
Reverse Gate – Source Voltage	V _{SG}		30	V
Reverse Drain – Source Voltage	V _{SD}		25	V
Power Dissipation	P _{tot}	T _c = 120 °C	500	W
Storage Temperature	T _{stg}		-55 to 250	°C

Electrical Characteristics

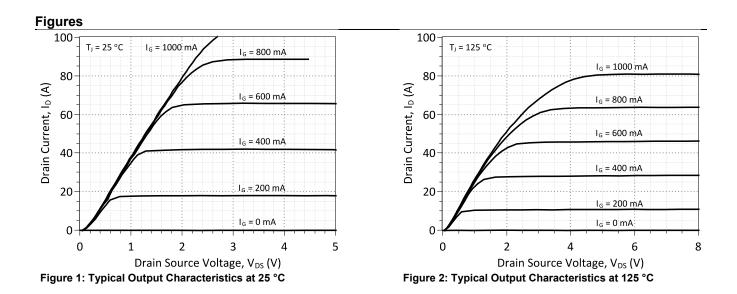
Deremeter	Sympol	Conditions -		Values		11:4
Parameter	Symbol	Symbol Conditions m		typ.	max.	Unit
On Characteristics						
Drain – Source On Voltage	V _{DS(ON)}	$\begin{array}{l} I_D = 50 \text{ A}, \ I_G = 1000 \text{ mA}, \ T_J = 25 \ ^\circ\text{C} \\ I_D = 50 \text{ A}, \ I_G = 1000 \text{ mA}, \ T_J = 125 \ ^\circ\text{C} \\ I_D = 50 \text{ A}, \ I_G = 2000 \text{ mA}, \ T_J = 175 \ ^\circ\text{C} \\ I_D = 50 \text{ A}, \ I_G = 2000 \text{ mA}, \ T_J = 250 \ ^\circ\text{C} \end{array}$		1.3 1.9 2.2 3.1		V
Drain – Source On Resistance	R _{DS(ON)}	$\begin{array}{l} I_{D} = 50 \text{ A}, \ I_{G} = 1000 \text{ mA}, \ T_{J} = 25 \ ^{\circ}\text{C} \\ I_{D} = 50 \text{ A}, \ I_{G} = 1000 \text{ mA}, \ T_{J} = 125 \ ^{\circ}\text{C} \\ I_{D} = 50 \text{ A}, \ I_{G} = 2000 \text{ mA}, \ T_{J} = 175 \ ^{\circ}\text{C} \\ I_{D} = 50 \text{ A}, \ I_{G} = 2000 \text{ mA}, \ T_{J} = 250 \ ^{\circ}\text{C} \end{array}$		25 39 43 62		mΩ
Gate Forward Voltage	$V_{GS(FWD)}$	I _G = 1000 mA, T _j = 25 °C I _G = 1000 mA, T _j = 250 °C		2.9 2.6		V
DC Current Gain	β	$\begin{array}{l} V_{DS} = 5 \mbox{ V, } I_D = 50 \mbox{ A, } T_j = 25 \mbox{ °C} \\ V_{DS} = 5 \mbox{ V, } I_D = 50 \mbox{ A, } T_j = 125 \mbox{ °C} \\ V_{DS} = 5 \mbox{ V, } I_D = 50 \mbox{ A, } T_j = 175 \mbox{ °C} \\ V_{DS} = 5 \mbox{ V, } I_D = 50 \mbox{ A, } T_j = 250 \mbox{ °C} \end{array}$		105 77 71 69		



Electrical Characteristics

Parameter	Symbol	Conditions -	Values			Unit
Parameter	Symbol Conditions		min.	typ.	max.	Unit
Off Characteristics						
Drain Leakage Current	I _{DSS}	$ \begin{array}{l} {V_{\rm{R}}} = 600 \; V, {V_{\rm{GS}}} = 0 \; V, {T_j} = 25 \; ^{\circ}{\rm{C}} \\ {V_{\rm{R}}} = 600 \; V, {V_{\rm{GS}}} = 0 \; V, \; {T_j} = 125 \; ^{\circ}{\rm{C}} \\ {V_{\rm{R}}} = 600 \; V, \; {V_{\rm{GS}}} = 0 \; V, \; {T_j} = 250 \; ^{\circ}{\rm{C}} \end{array} $		10 50 100		μA
Gate Leakage Current	I _{SG}	V _{SG} = 20 V, T _j = 25 °C		20		nA
Capacitance Characteristics						
Gate-Source Capacitance	C _{gs}	V _{GS} = 0 V, f = 1 MHz		3000		pF
Input Capacitance	C _{iss}	V_{GS} = 0 V, V_{D} = 1 V, f = 1 MHz		3500		pF
Reverse Transfer/Output Capacitance	C _{rss} /C _{oss}	V _D = 1 V, f = 1 MHz		2100		pF
Turn On Delay Time Rise Time	t _{d(on)} t _r	$T_{j} = 25 \text{ °C}, V_{DS} = 400 \text{ V}, I_{D} = 50 \text{ A},$ Two-Level Gate Drive,		55 50		ns ns
Switching Characteristics				r	r	
Turn Off Delay Time	1	$R_G = 1.5 \Omega$, $C_G = 32 nF$,		75		ns
Fall Time	t _{d(off)} t _f	V _{GH} = 18 V, V _{GL} = 6.5 V, V _{EE} = -10 V,		40		ns
Turn-On Energy Per Pulse	E _{on}	IXDD614 Gate Drive IC, L = 287 µH, FWD = GB50SLT12,		1.6		mJ
Turn-Off Energy Per Pulse	E _{off}	Refer to Fig. 15 for gate current		0.55		mJ
Total Switching Energy	E _{ts}	waveform		2.15	1	mJ
Turn On Delay Time	t _{d(on)}	T _i = 250 °C, V _{DS} = 400 V, I _D = 50 A,		55		
Rise Time	tr	Two-Level Gate Drive,		30		ns
Turn Off Delay Time	t _{d(off)}	R_{G} = 1.5 Ω, C_{G} = 32 nF,		75		ns
Fall Time	t _f	V _{GH} = 18 V, V _{GL} = 6.5 V, V _{EE} = -10 V, IXDD614 Gate Drive IC.		30		ns
Turn-On Energy Per Pulse	Eon	$L = 287 \mu\text{H}, FWD = GB50SLT12,$		0.3		mJ
Turn-Off Energy Per Pulse	E _{off}	Refer to Fig. 15 for gate current		0.4		mJ
Turn-Oil Energy Per Pulse	E _{ts}	waveform		0.7		mJ

Thermal resistance, junction - case	R _{th-IC}	0.26	°C/W



GA50JT06-258

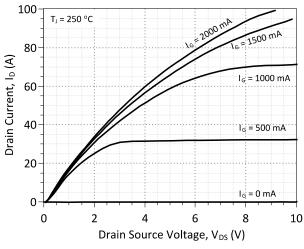
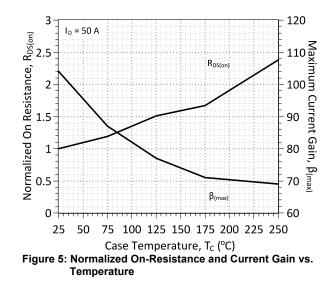
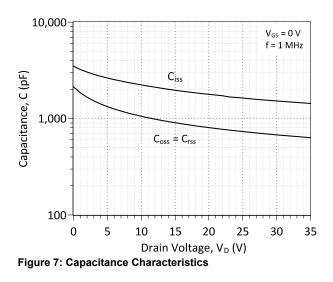


Figure 3: Typical Output Characteristics at 250 °C





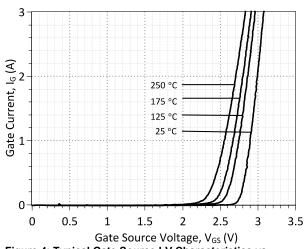
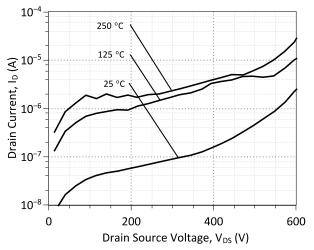
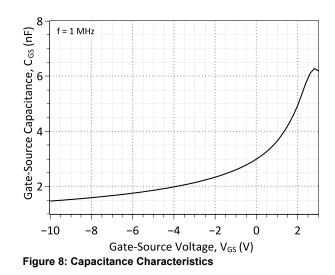


Figure 4: Typical Gate Source I-V Characteristics vs. Temperature







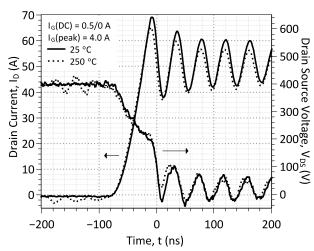
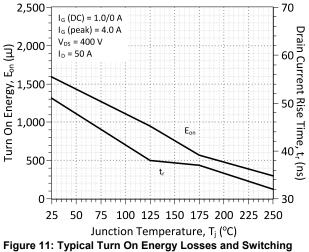
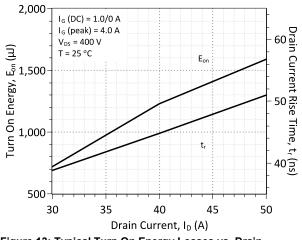
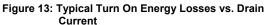


Figure 9: Typical Hard-switched Turn On Waveforms



Times vs. Temperature





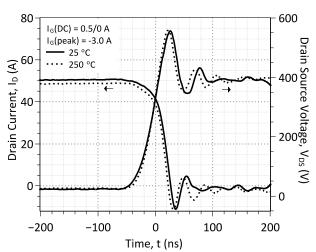
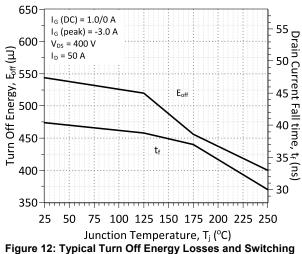
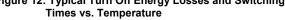
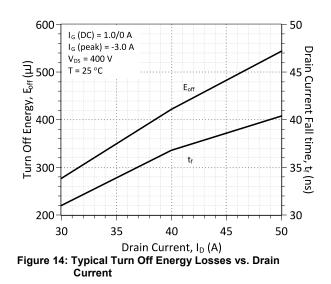


Figure 10: Typical Hard-switched Turn Off Waveforms









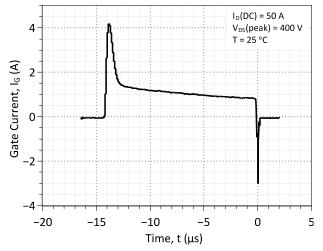
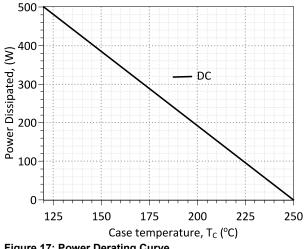
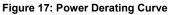
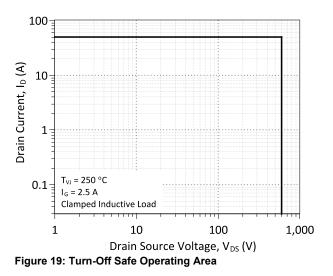


Figure 15: Typical Gate Current Waveform







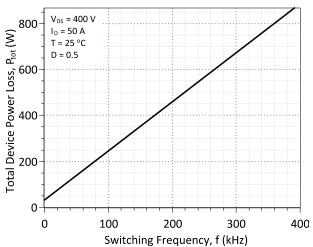


Figure 16: Typical Hard Switched Device Power Loss vs. Switching Frequency

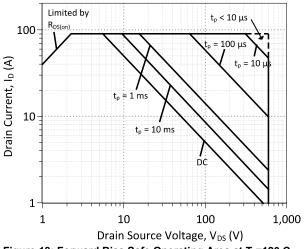
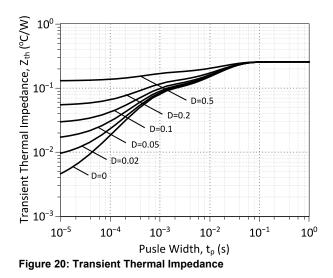


Figure 18: Forward Bias Safe Operating Area at Tc=120 C



¹ - Representative values based on device switching energy loss. Actual losses will depend on gate drive conditions, device load, and circuit topology.

Commercial Gate Drivers Compatible with GA50JT06-258

			Features					
Manufacturer	Part Number	Peak Current Output	Optical Signal Isolation	Desaturation Detection	Under Voltage Lockout	Active Miller Clamping		
Avago Tech.	HCPL-316J	2.5	\checkmark	\checkmark	\checkmark	-		
Avago Tech.	HCPL-322J	2.5	\checkmark	✓	\checkmark	\checkmark		
IXYS	IXD_604	4.0	-	-	-	-		
IXYS	IXD_609	9.0	-	-	-	-		
IXYS	IXD_614	14.0	-	-	-	-		
IXYS	IXD_630	30.0	-	-	-	-		
IXYS	IRFD630	30.0	-	-	-	-		
Micrel	MIC4452YN	12.0	_	_	_	_		
Microsemi	LX1780QLQ	15.0	_	_	✓	_		
Texas Instruments	UCC27322	9.0	_	_	_	_		

This is a partial list of widely available commercial Silicon IGBT/MOSFET gate drivers which may be used to drive the GA50JT06-258. Specific product information including advanced features and pinouts should be obtained from the individual product manufacturer's websites.

The gate of the GA50JT06-258 can be driven similar to a silicon IGBT or MOSFET in which a gate driver IC is used to supply positive gate current peaks to the device at turn-on and negative current peaks at turn-off. Unlike the IGBT or MOSFET, the GA50JT06-258 also requires a continuous gate current for the device to remain on after the initial current peak. An example gate current waveform for the GA50JT06-258 can be seen in Fig. 15.

Single-Level SJT Gate Drive

Producing the necessary gate current peaks and continuous currents can be done very simply using a circuit similar what is shown in Fig. 21 in which an external gate capacitor and resistor are placed in parallel connected to the gate drive output node and the SJT gate. The gate resistor is chosen to control the continuous gate current and adjusting the external capacitance will alter positive and negative current peaks. More details can be found in a series of GeneSiC Semiconductor Application Notes. (http://www.genesicsemi.com/index.php/references/notes)

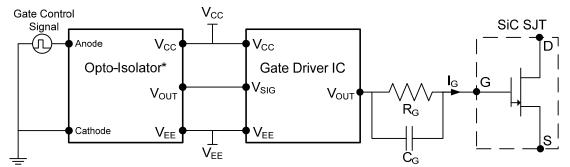


Figure 21: Single-Level SJT Gate Diver Configuration (* - External signal isolation is required for non-isolated gate driver ICs.)

Single-Level Gate Drive Conditions

Devemeter	Symbol	Conditions		Values		Unit	
Parameter	Symbol	Conditions	Min.	Optimum	Max.		
Supply Voltage	V _{CC}		10	20		V	
Negative Supply Voltage	V _{EE}		-10	-8	GND	V	
Output Current, Peak	I _{OUT, pk}	Package Limited,	2.0	4.0		А	
Output Current, Continuous	I _{OUT}	T = 175 °C	0.7	1.0		А	

Output Gate Components

Gate Resistance	R_{G}	V_{CC} = 20 V, $I_{G} \approx 1.0$ A, T = 175 °C	15	15	Ω
Gate Capacitance	C_{G}	V_{CC} = 20 V I _{G,pk} ≈ 4.0 A, T = 175 °C	20	32	nF

GA50JT06-258

Two-Level SJT Gate Drive

The gate of the GA50JT06-258 can also be driven with a slightly more advanced gate drive circuit, seen in Fig. 22, in which two gate drive ICs are used with two different supply voltage (V_{CC}) levels in order to minimize gate drive losses. By using a second, lower voltage output gate driver IC the power consumption of the continuous current is reduced. Additional detail on this Two-Level SJT gate driving technique is discussed in GeneSiC Semiconductor Application Note AN-10B. (http://www.genesicsemi.com/index.php/references/notes)

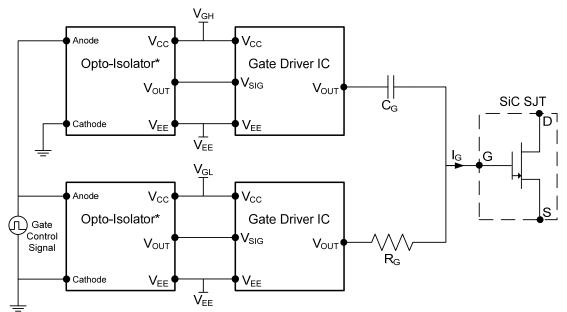


Figure 22: Two-Level SJT Gate Diver Configuration for Reduced Drive Losses (* – External signal isolation is required for nonisolated gate driver ICs.)

Two-Level Gate Drive Conditions

Parameter	Symbol	Conditions		Values		Unit
Farameter	Symbol	Conditions	min.	Optimum	max.	
Supply Voltage, High Level Driver	$V_{CC} (V_{GH}^{+})$		15	20		V
Supply Voltage, Low Level Driver	$V_{CC}(V_{GL}^{+})$		5	6.5		V
Negative Supply Voltage	V _{EE}			-10	GND	V
Output Current, Peak	I _{OUT}	Package Limited	2.0	4.0		А
Output Current, Continuous	Ι _{ουτ}	T = 175 °C	0.7	1.0		А

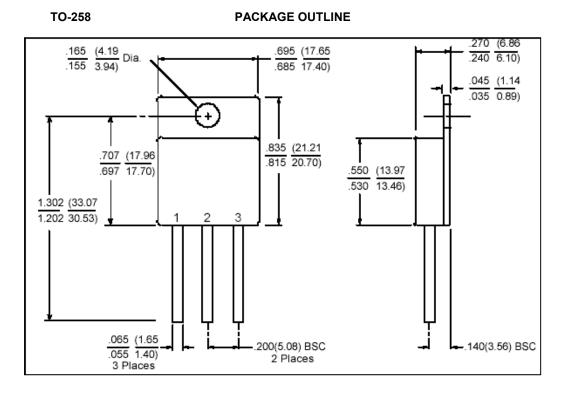
Output Gate Components

Gate Resistance	R_{G}	V _{GL} = 6.5 V, I _G ≈ 1.0 A, T = 175 °C		1.5	4	Ω
Gate Capacitance	C _G	V _{GH} = 20 V, I _{G,pk} ≈ 4.0 A, T = 175 ^o C	20	32		nF

+ – Consult application note AN-10B for more information on parameters V_{GH} and V_{GL} .



Package Dimensions:



NOTE

1. CONTROLLED DIMENSION IS INCH. DIMENSION IN BRACKET IS MILLIMETER.

2. DIMENSIONS DO NOT INCLUDE END FLASH, MOLD FLASH, MATERIAL PROTRUSIONS

Revision History						
Date	Revision	Comments	Supersedes			
2013/12/19	1	Updated Gate Drive Section				
2013/12/05	0	Initial release				

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SPICE Model Parameters

This is a secure document. Copy this code from the SPICE model PDF file on our website into a SPICE software program for simulation of the GA50JT06.

```
*
     MODEL OF GeneSiC Semiconductor Inc.
*
*
     $Revision: 1.0
                                $
*
     $Date: 05-DEC-2013
                                $
    GeneSiC Semiconductor Inc.
*
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    43670 Trade Center Place Ste. 155
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    Dulles, VA 20166
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* These models are provided "AS IS, WHERE IS, AND WITH NO WARRANTY
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* TO ANY IMPLIED WARRANTIES OF MERCHANTABILITY AND FITNESS FOR A
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* Models accurate up to 2 times rated drain current.
*
.model GA50JT06 NPN
+ IS
         5.00E-47
+ ISE
         1.26E-28
          3.23
+ EG
+ BF
         100
         0.55
+ BR
+ IKF
         3500
+ NF
         1
+ NE
         2
         0.26
+ RB
         0.01
+ RE
         0.011
+ RC
         1.75E-9
+ CJC
+ VJC
          3
         0.5
+ MJC
         5.57E-9
+ CJE
+ VJE
         3
         0.5
+ MJE
+ XTI
          3
+ XTB
          -1.2
+ TRC1
+ VCEO
         7.00E-3
         600
+ ICRATING 50
+ MFG GeneSiC Semiconductor
*
* End of GA50JT06 SPICE Model
```